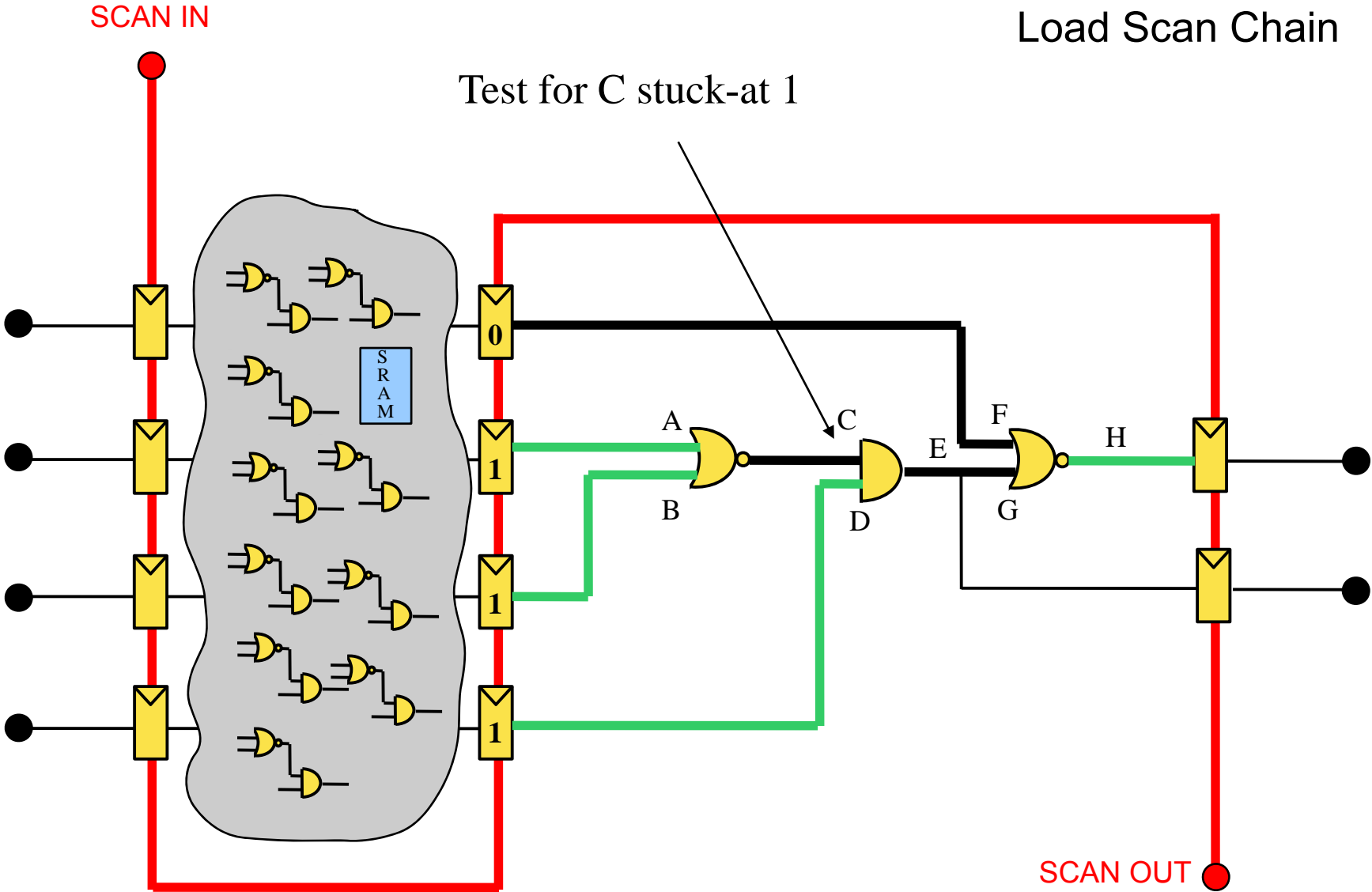


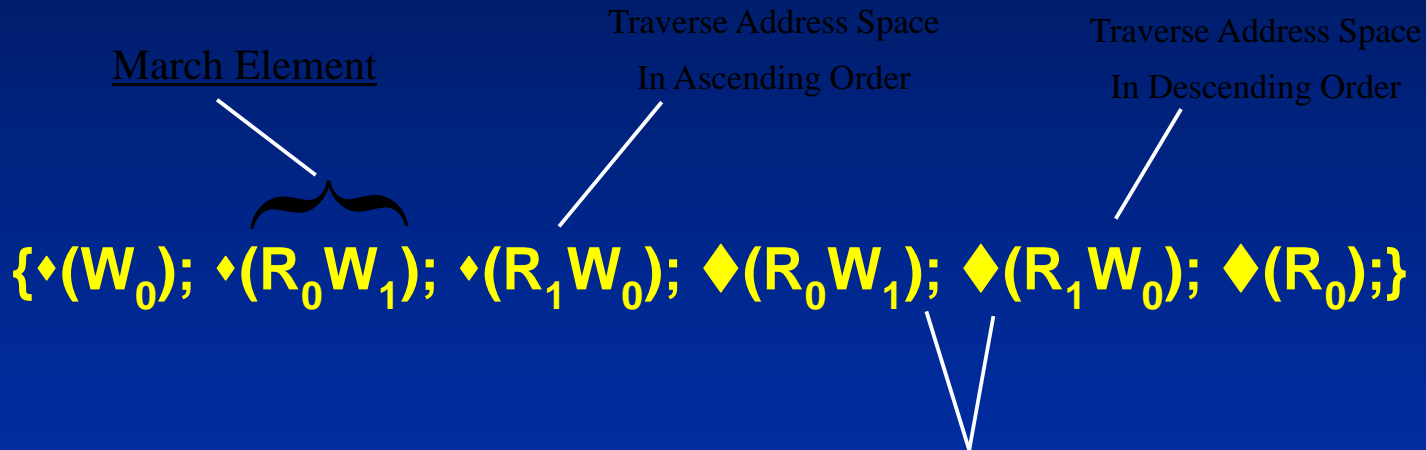
Stuck-At Testing



MBIST Test Algorithm

March C -

Ref A.J. Van de Goor "Testing Semiconductor Memories"



DC Faults Covered

- .Address Faults
- .Stuck-at Faults
- .Transition Faults
- .Coupling Faults
- .Unlinked Coupling Faults

Bitwise Opposite Data Patterns
Not Restricted to All Ones and All Zeros

AC Testing

- .Write Recovery